

<b>Notice of References Cited</b>	Application/Control No. <b>08/905,293</b>	Applicant(s)/Patent Under Reexam <b>Yelton et al.</b>
	Examiner <b>S. Devi, Ph.D.</b>	Art Unit <b>1645</b>

**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>
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<b>N</b>	WO 93/02702	02/18/93	PCT	Gundel et al.	----
<b>O</b>					
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